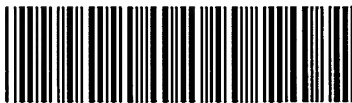


Search Notes

Application/Control No.

10/563,576

Examiner

David Mis

Applicant(s)/Patent under
Reexamination

EYRIES ET AL.

Art Unit

2817

SEARCHED

Class	Subclass	Date	Examiner
332	100-102	7/12/2006	DM

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
USPGPUB	(see	7/12/2006	DM
	history)		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR